

RAM Mounts Testing Summary

RAM[®] Form-Fit Holder for Zebra ET6x

Products Covered

Accompanying Power Supplies

RAM-HOL-ZE25LU RAM-HOL-ZE25PD2HLU RAM-HOL-ZE25PD2HU RAM-HOL-ZE25PD2LU RAM-HOL-ZE25PD2U RAM-HOL-ZE25PDHLU RAM-HOL-ZE25PDHU RAM-HOL-ZE25PDU RAM-HOL-ZE25PHU RAM-HOL-ZE25PLU RAM-HOL-ZE25PU RAM-HOL-ZE25PU

RAM-GDS-CHARGE-V9U

RAM-GDS-CHARGE-V10U



Test	Description
Vibration – operational	MIL-STD-810H, Method 514.8, Table 514.8C-VII, Category 4. Tested performed with unlocked dock and device oriented vertical, transverse, and longitudinal. 1 hour each axis, 3 hours total.
Functional Shock - operational	MIL-STD-810H, Method 516.8, Procedure 1, 3 positive and 3 negative pulses per vertical, longitudinal, and transverse axis. 18 total pulses. Pulses are 20G, 11ms terminal peak sawtooth.
Pogo Pins – Cycle rating	Pogo pins rated to 100k cycles
USB Validation Protocol, Speed, Power	NPI Developed Testing Specification for USB 2.0 Compliance up to 480Mbps, 4.75-5.25VDC @ 900mA per port
Power Supply Input Voltage Tolerance	NPI Developed Testing Specification for Cycle Testing of Input Voltage and variable current
Power Supply Output Voltage Tolerance	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
Power Supply Load Test	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
Regulatory Compliance	FCC, IC CE, RoHS, WEEE
Safety, Emission, Immunity (Ram Power Supply)	CE EN:55032, EN 55035, IEC 61000-6-1, EN 62368-1, e-Mark

Official NPI testing documentation. Tests performed onsite by NPI engineers.